

PC S/W	Firmware	PC Software Change Details	Instrument Firmware Change Details
V1.1.12.1669	0019	<p>Added Graph for BJT: <math>I_C / V_{BE}</math>.</p> <p>Improved graph trace drawing order.</p> <p>Added global graph font size adjustment.</p> <p>Added labels to PN graph.</p> <p>Added "spare lead" control selection to PN graph.</p> <p>Added lock and auto-set for graph parameters.</p> <p>Added "right-click" option to lock traces (to aid part matching etc.).</p> <p>Allows swap of Drain/Source for JFET graphs.</p> <p>Improved Vreg graphs now compensate for voltage dropped across ground current sense resistor.</p> <p>Improved constant current and constant voltage iteration when close to graph limits.</p> <p>Added user-defined graph title (useful for printing).</p> <p>Added user-defined naming of graph traces (with optional auto-numbering that can increment on every graph start).</p> <p>Added user-defined component names (with optional auto-numbering that can increment on every component identification).</p> <p>Added option to show/hide graph legend.</p> <p>Added option to delete all traces on all graphs.</p> <p>Added graph options to graph menu (in addition to "right-click" context menu).</p> <p>Added colours to all lead identities.</p> <p>Added tool-tips of graph parameter limits and other items.</p> <p>Improved tool-tip behaviour and extended display duration.</p>	<p>IGBT detection improved for very high current devices.</p> <p>Measures <math>V_{CE(SAT)}</math> saturation voltage for BJTs at <math>I_B=1mA</math> and <math>I_C=5mA</math> (displayed if <math>h_{FE}&gt;10</math>).</p> <p>Measures <math>V_{CE(SAT)}</math> saturation voltage for digital transistors at <math>V_{BE}=5V</math> and <math>I_C=5mA</math>.</p> <p>Measures <math>V_{CE(SAT)}</math> saturation voltage for IGBTs at <math>V_{GE}=5V</math> and <math>I_C=5mA</math>.</p> <p>Measures <math>R_{DS(ON)}</math> for JFETs (to 1Ω resolution) at <math>V_{GS}=0V</math> and <math>I_D=5mA</math> typically.</p> <p>Measures <math>R_{DS(ON)}</math> for MOSFETs (to 1Ω resolution) at <math>V_{GS}=8V</math> and <math>I_D=5mA</math> typically.</p> <p>Improved constant current and constant voltage iteration when close to test limits.</p> <p>Added SCR reverse conduction rejection test. This helps to reject parts that exhibit SCR-like latch-up.</p> <p>Increased acceptable Germanium leakage current from 2mA to 3mA.</p> <p>Improved detection of Silicon/Germanium semiconductor type for BJTs which helps with some silicon power transistors that have a very low <math>V_{BE}</math>.</p> <p>Increased regulator quiescent current limit from 5mA to 6mA.</p> <p>Increased regulator dVout limit from 10% to 20% (to help cope with regulators that are less stable when tested on the DCA75).</p> <p>Displays warning if regulator dVout&gt;5%.</p>
V1.1.11.1294	0018	<p>Added clearer parameter labels for V/I graphs.</p> <p>Added dVout descriptions in text pane for regulators.</p> <p>Streamlined software download process.</p> <p>Streamlined firmware upgrade process.</p> <p>Improvement in speed of some graph types.</p>	<p>JFET <math>I_{DSS}</math> measurement now at defined for <math>V_{DS}</math> of 3V.</p> <p>JFET and MOSFET Transconductance measurement now at constant <math>V_{DS}</math> of 3V.</p> <p>JFET and MOSFET <math>I_{D(OFF)}</math> threshold is now 5µA.</p> <p>Improved "Digital Level" transistor support.</p>
V1.1.10.1270	0017	Support for new firmware	Correction of firmware upgrade process for early revision units.
V1.1.9.1263	0016	<p>Added dVout measurement for regulators.</p> <p>Support for new firmware.</p>	<p>Improved regulator support for some with unstable Vout.</p> <p>Added dVout measurement for regulators.</p> <p>Improved diode network detections.</p> <p>Added new diode network symbols.</p> <p>Improved asymmetric JFET detection.</p>
	0015	Support for new firmware.	Update to LCD code to support different LCD chip set.
V1.1.8.1166	0014	Support for new firmware.	<p>Improved support for MOSFETs with high <math>R_{DS(on)}</math>.</p> <p>Improved support for MOSFETs with high body diode voltage.</p> <p>Improved support for protected-gate IGBTs.</p> <p>Improved Depletion/Enhancement mode differentiation.</p>
V1.1.7.1126	0013	<p>Corrected graph tool-tips for different localisations.</p> <p>Support for new firmware.</p>	<p>Improved IGBT detection.</p> <p>Improved SCR and Triac detection especially for very sensitive types.</p> <p>Improved performance of boost converter when running on battery power.</p>
V1.1.6.1115	0012	Support for new firmware.	<p>Improved detection of germanium transistors that have high reverse collector-emitter leakage current.</p> <p>Correction of diode network detection.</p> <p>Improved SCR and Triac detection.</p>
V1.1.5.985	0011	<p>Added symbols for MOSFETs with body diodes.</p> <p>Corrected <math>I_B</math> labels on curve tracing settings.</p> <p>Added <math>V_{CE}</math>, <math>V_{D0}</math> and <math>V_S</math> labels to test circuit diagrams.</p>	<p>Added symbols for MOSFETs with body diodes.</p> <p>Increased scrolling speed.</p>
V1.1.4.956	0010	<p>Improved memory management.</p> <p>Minor label adjustment for graphs.</p> <p>Log/Linear span for MOSFET <math>V_{GS}</math> option.</p> <p>Added Graphs:</p> <ul style="list-style-type: none"> <li>Vreg: <math>I_D/V_{IN}</math></li> <li>IGBT: <math>I_C/V_{CE}</math></li> <li>IGBT: <math>I_C/V_{GE}</math></li> </ul>	<p>Added "digital" transistor support including measurement of both internal resistances.</p> <p>Improved support for MOSFETs with high <math>R_{DS(on)}</math>.</p> <p>Improved text line spacing.</p>
V1.1.3.924	0009	<p>Improved measurement of germanium leakage during <math>H_{FE}</math> graphing.</p> <p>Improved graph scaling.</p> <p>Minor label adjustment for text entry.</p>	
V1.1.2.840	0009	Support for new firmware.	<p>LCD initialisation optimisation.</p> <p>Improved depletion mode support.</p> <p>Improved voltage regulator support.</p> <p>JFET PN junction threshold adjustment for improved SiC support.</p>
V1.1.1.834	0008	Improved USB disconnection handling.	
V1.1.0.815	0008	<p>Added config option to JFET Graphs.</p> <p>Added Graphs:</p> <ul style="list-style-type: none"> <li>BJT: <math>h_{FE}/V_{CE}</math></li> <li>BJT: <math>h_{FE}/I_C</math></li> </ul> <p>Added multiple traces to JFET <math>I_B / V_{GS}</math> graph.</p> <p>Allow colour change of traces.</p> <p>Added graph printing.</p> <p>Added graph loading &amp; saving.</p> <p>Added circuit diagrams of test conditions.</p>	<p>Improved MOSFET detection, including support for protected/smart gate types.</p> <p>Improved USB Suspend behaviour.</p> <p>Optimised BJT tests to limit reverse bias to 5V.</p>
V1.0.4.737	0007	<p>Simplified Windows® 8 installation process.</p> <p>Auto scaling of graphs improved, particularly for small parameters.</p>	Improved support for bi-colour LEDs that have very symmetrical forward/reverse characteristics.
V1.0.3.720	0006	<p>Includes optional automatic update checking.</p> <p>Support for new firmware.</p>	<p>Corrected sound on/off settings.</p> <p>Improved support for JFETs with highly non-symmetrical characteristics.</p> <p>Implemented 5mA constant current tests for bipolar transistor <math>V_{BE}</math> measurements (rather than resistive drive).</p>
V1.0.2.0	0005	Improved number format support for international Windows®.	Improved support for JFETs that have saturation currents of less than 5mA.
V1.0.0.0	0004-5	Original Release.	Original Release (0005 included mods for factory use only).

Upgrades for the DCA75 can be performed by the user. Please contact us if you require assistance.  
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